The information below reflects a change that is being implemented.

	Notice Date:		02/13/2002	
Product Category:			24x	XX
Notification Subject: Change #344_1 -				
32K & 64K Serial EEPROM				
Notification Body: CCB #: 344-1 Microchip Part # (New): See				
"Description of Change" Microchip Part # (Old): See "Description of Change" Projected Ship				
Date of Revised Device: 4/1/02 Description of Change: The I2C EEPROMs listed below will be				
moved from the current 121K (0.7 micron) fabrication process to the new 150K (0.5 micron)				
process. In order to continue receiving devices from the current 121K process, the revised part				
numbers listed below must be used. If an order is received using the current part numbers, the				
new devices from the 150K process will be shipped. The devices affected include all voltages,				
temperatures and packages of the following part numbers: PART # (150K) REVISED PART #				
(121K) 24LC64-x/xx 24LC64-x/xxRVA 24AA64-x/xx 24AA64-x/xxRVA PART # (150K) REVISED				
PART # (121K) 24LC32A-x/xx 24LC32A-x/xxRVB 24AA32A-x/xx 24AA32A-x/xxRVB Impacts to				
Data Sheet: The 8-lead MSOP and the 8-lead TSSOP package in a standard pinout configuration				
will be added. The specification for 2.5 volt operation over the automotive temperature range will				
be added. 400 KHz operation at an operating voltage of 2.5 volts will be added. Reason for				
Change: To allow the addition of the MSOP and standard pinout TSSOP packages at these				
higher densities. Markings to Distinguish Revised From Unrevised Devices: (e.g.: Date Code,				
Device Marking, Ship Container Marking) NONE Summary of Qualification Results: Meets or				
exceeds all requirements of the Worldwide Quality Conformance Specification, QCI-39000;				
including ESD, latchup, endurance, retention, and dynamic life testing. 24LC64 / 24AA64 : Report # C-0202124 24LC32A / 24AA32A : Report # C-0202521 Additional Comments: Revised part				
numbers will give customers the option of ordering memory from the older process without				
interruption.				
interruption.				